

UNISONIC TECHNOLOGIES CO., LTD

5NM120 Preliminary Power MOSFET

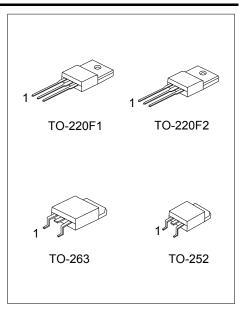
5.0A, 1200V N-CHANNEL SUPER-JUNCTION MOSFET

■ DESCRIPTION

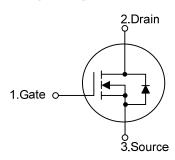
The UTC **5NM120** is a Super Junction MOSFET Structure and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and a high rugged avalanche characteristics. This power MOSFET is usually used at AC-DC converters for power applications.

■ FEATURES

- * $R_{DS(ON)} \le 2.3 \Omega @ V_{GS} = 10V, I_D = 2.5A$
- * High Switching Speed



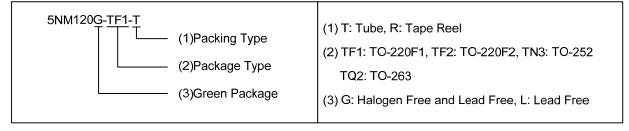
■ SYMBOL



■ ORDERING INFORMATION

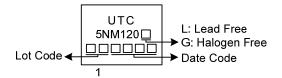
Ordering Number		Dealtons	Pin Assignment			Deaking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
5NM120L-TF1-T	5NM120G-TF1-T	TO-220F1	G	D	S	Tube	
5NM120L-TF2-T	5NM120G-TF2-T	TO-220F2	G	D	S	Tube	
5NM120L-TN3-R	5NM120G-TN3-R	TO-252	G	D	S	Tape Reel	
5NM120L-TQ2-T	5NM120G-TQ2-T	TO-263	G	D	S	Tube	
5NM120L-TQ2-R	5NM120G-TQ2-R	TO-263	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source



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■ MARKING



■ ABSOLUTE MAXIMUM RATINGS (unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	1200	V
Gate-Source Voltage		V_{GSS}	±30	V
Continuous Drain Current	Continuous	I_{D}	5	Α
	Pulsed	I _{DM} 10		Α
Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	95	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	2	V/ns
Power Dissipation	TO-220F1 TO-220F2)	26	W
	TO-252	P _D	35	W
	TO-263		45	W
Junction Temperature		TJ	+150	°C
Storage Temperature		T _{STG}	-55 ~ +150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L = 100mH, I_{AS} = 1.37A, V_{DD} = 50V, R_G = 25 Ω Starting T_J = 25°C
- 4. $I_{SD} \le 5.0$ A, di/dt ≤ 200 A/ μ s, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25$ °C

■ THERMAL DATA

PARAMETER		SYMBOL	RATING	UNIT
Junction to Ambient	TO-220F1 TO-220F2		62.5	°C/W
	TO-252	θ_{JA}	110	°C/W
	TO-263		62.2	°C/W
hundian to Occa	TO-220F1 TO-220F2	0	4.8	°C/W
Junction to Case	TO-252	θις	3.57 (Note)	°C/W
	TO-263		2.77	°C/W

Note: Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

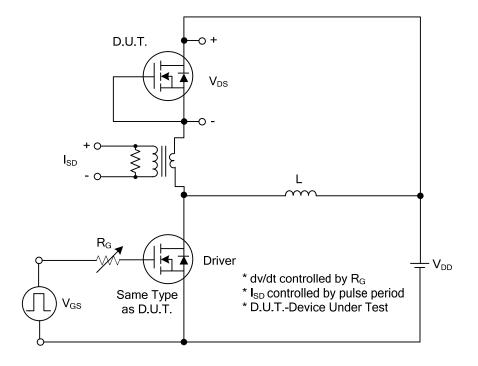
■ ELECTRICAL CHARACTERISTICS

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV _{DSS}	I _D =250μA, V _{GS} =0V	1200			V
Drain-Source Leakage Current		I _{DSS}	V _{DS} =1200V, V _{GS} =0V			10	μΑ
Gate-Source Leakage Current	Forward		V_{GS} =+30V, V_{DS} =0V			+100	nA
	Reverse	I_{GSS}	V _{GS} =-30V, V _{DS} =0V			-100	nΑ
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	2.5		4.5	V
Static Drain-Source On-State Resistance		R _{DS(ON)}	V _{GS} =10V, I _D =2.5A			2.3	Ω
DYNAMIC PARAMETERS							
Input Capacitance		C _{ISS}			535		pF
Output Capacitance		Coss	V _{GS} =0V, V _{DS} =50V, f=1.0MHz		33		pF
Reverse Transfer Capacitance		C _{RSS}			2.5		pF
SWITCHING PARAMETERS					_		
Total Gate Charge		Q_G	V 000V V 40V I 50A		24		nC
Gate to Source Charge		Q_GS	V _{DS} =960V, V _{GS} =10V, I _D =5.0A		7		nC
Gate to Drain Charge		Q_{GD}	(Note 1, 2)		6.6		nC
Turn-ON Delay Time		t _{D(ON)}			8		ns
Rise Time		t _R	V _{DD} =100V, V _{GS} =10V, I _D =5.0A,		18		ns
Turn-OFF Delay Time		t _{D(OFF)}	R _G =25Ω (Note 1, 2)		65		ns
Fall-Time		t _F			39		ns
SOURCE- DRAIN DIODE RAT	INGS AND C	HARACTER	ISTICS		_		
Maximum Body-Diode Continuous Current		Is				5	Α
Maximum Body-Diode Pulsed Current		I _{SM}				10	Α
Drain-Source Diode Forward Voltage		V_{SD}	I _S =5.0A, V _{GS} =0V			1.4	V
Body Diode Reverse Recovery Time		t _{rr}	I _S =5.0A, V _{GS} =0V,		500		ns
Reverse Recovery Charge		Q _{rr}	dI _F /dt=100A/μs (Note 1)		5.8		μC
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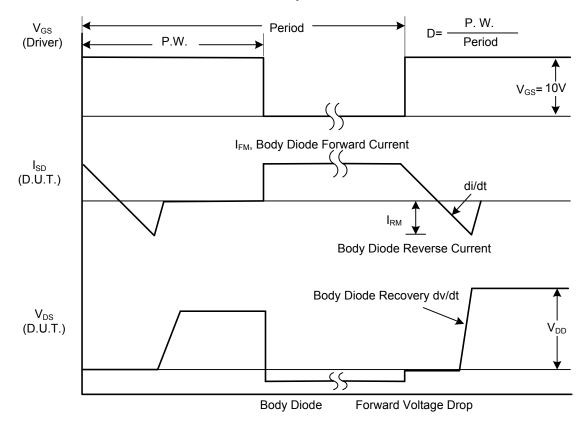
Notes: 1. Pulse Test: Pulse width ≤ 1200µs, Duty cycle ≤ 2%.

^{2.} Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

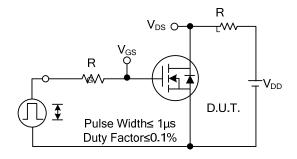


Peak Diode Recovery dv/dt Test Circuit

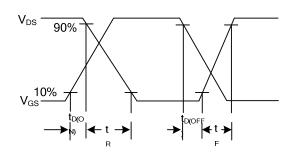


Peak Diode Recovery dv/dt Waveforms

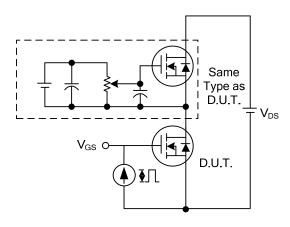
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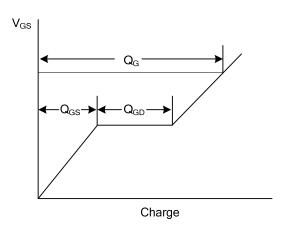
Switching Test Circuit



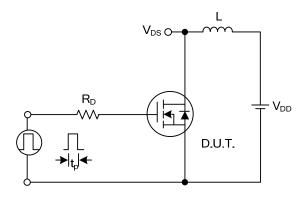
Switching Waveforms



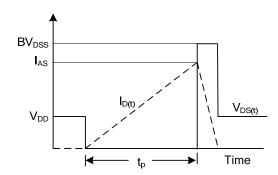
Gate Charge Test Circuit



Gate Charge Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

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